# ICX285AQ

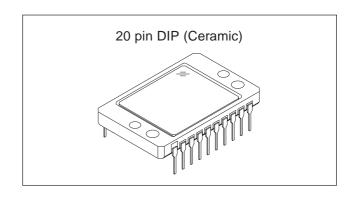
# Diagonal 11mm (Type 2/3) Progressive Scan CCD Image Sensor with Square Pixel for Color Cameras

# Description

The ICX285AQ is a diagonal 11mm (Type 2/3) interline CCD solid-state image sensor with a square pixel array. High sensitivity and low smear are achieved through the adoption of EXview HAD CCD technology. Progressive scan allows all pixels' signals to be output independently within approximately 1/15 second. Also, the adoption of high frame rate readout mode supports 60 frames per second. This chip features an electronic shutter with variable charge-storage time which makes it possible to realize full-frame still images without a mechanical shutter.

High resolution and high color reproductively are achieved through the use of R, G, B primary color mosaic filters.

This chip is suitable for image input applications such as still cameras which requires high resolution, etc.



#### Features

- Progressive scan allows individual readout of the image signals from all pixels.
- High horizontal and vertical resolution (both approximately 800 TV-lines) still images without a mechanical shutter
- Supports high frame rate readout mode (effective 256 lines output, 60 frames/s)
- Square pixel
- Aspect ratio: 4:3
- Horizontal drive frequency: 28.64MHz
- R, G, B primary color mosaic filters on chip
- High sensitivity, low smear
- Low dark current, excellent anti-blooming characteristics
- Continuous variable-speed shutter function
- Horizontal register: 5.0V drive

# Pin 1 2 V Pin 11 H 40

Optical black position (Top View)

#### **Device Structure**

• Interline CCD image sensor

• Image size: Diagonal 11mm (Type 2/3)

• Total number of pixels: 1434 (H)  $\times$  1050 (V) approx. 1.50M pixels • Number of effective pixels: 1392 (H)  $\times$  1040 (V) approx. 1.45M pixels • Number of active pixels: 1360 (H)  $\times$  1024 (V) approx. 1.40M pixels

• Chip size: 10.2mm (H)  $\times$  8.3mm (V) • Unit cell size: 6.45 $\mu$ m (H)  $\times$  6.45 $\mu$ m (V)

• Optical black: Horizontal (H) direction: Front 2 pixels, rear 40 pixels Vertical (V) direction: Front 8 pixels, rear 2 pixels

Number of dummy bits: Horizontal 20

Vertical 3

• Substrate material: Silicon

# **EXview HAD CCD**<sub>TM</sub>

\* EXview HAD CCD is a trademark of Sony Corporation.

EXview HAD CCD is a CCD that drastically improves light efficiency by including near infrared light region as a basic structure of HAD (Hole-Accumulation-Diode) sensor.

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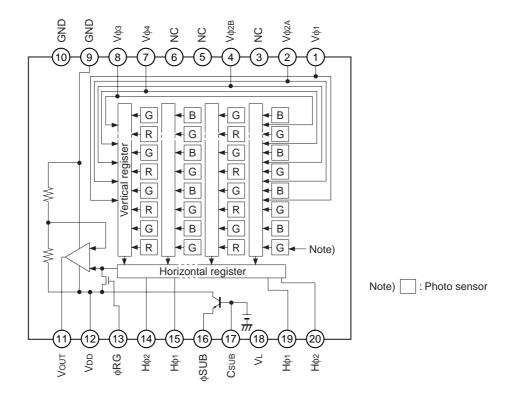
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# **Block Diagram and Pin Configuration** (Top View)



# **Pin Description**

Pin No.	Symbol	Description	Pin No.	Symbol	Description
1	Vф1	Vertical register transfer clock	11	Vouт	Signal output
2	Vф2A	Vertical register transfer clock	12	VDD	Supply voltage
3	NC		13	φRG	Reset gate clock
4	Vф2B	Vertical register transfer clock	14	Нф2	Horizontal register transfer clock
5	NC		15	Нф1	Horizontal register transfer clock
6	NC		16	φSUB	Substrate clock
7	Vф4	Vertical register transfer clock	17	Сѕив	Substrate bias*1
8	Vфз	Vertical register transfer clock	18	VL	Protective transistor bias
9	GND	GND	19	Нф1	Horizontal register transfer clock
10	GND	GND	20	Нф2	Horizontal register transfer clock

<sup>\*1</sup> DC bias is generated within the CCD, so that this pin should be grounded externally through a capacitance of 0.1µF.

# **Absolute Maximum Ratings**

	Item	Ratings	Unit	Remarks
	Vdd, Vout, фRG – фSUB	-40 to +12	V	
	Vφ2A, Vφ2B – φSUB	-50 to +15	V	
Against φSUB	$V\phi_1, V\phi_3, V\phi_4, V_L - \phi SUB$	-50 to +0.3	V	
	Hφ1, Hφ2, GND – φSUB	-40 to +0.3	V	
	Csub – $\phi$ SUB	-25 to	V	
	Vdd, Vout, фRG, Csub – GND	-0.3 to +22	V	
Against	Vφ1, Vφ2A, Vφ2B, Vφ3, Vφ4 – GND	-10 to +18	V	
	Hφ1, Hφ2 – GND	-10 to +6.5	V	
Against +\/-	Vф2A, Vф2B — VL	-0.3 to +28	V	
Against φV∟	$V\phi_1, V\phi_3, V\phi_4, H\phi_1, H\phi_2, GND - V_L$	-0.3 to +15	V	
	Voltage difference between vertical clock input pins	to +15	V	*1
Between input clock pins	Hφ1 – Hφ2	-6.5 to +6.5	V	
Clock pillo	Hφ1, Hφ2 – Vφ4	-10 to +16	V	
Storage tempera	ature	-30 to +80	°C	
Guaranteed tem	perature of performance	-10 to +60	°C	
Operating temper	erature	-10 to +75	°C	

 $<sup>^{*1}</sup>$  +24V (Max.) when clock width < 10 $\mu$ s, clock duty factor < 0.1%.

# **Bias Conditions**

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Supply voltage	VDD	14.55	15.0	15.45	V	
Protective transistor bias	VL		*2			
Substrate clock	φSUB		*3			
Reset gate clock	φRG		*3			

<sup>\*2</sup> VL setting is the VvL voltage of the vertical clock waveform, or the same voltage as the VL power supply for the V driver should be used.

#### **DC Characteristics**

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Supply current	IDD		9	11	mA	

<sup>+16</sup>V (Max.) is guaranteed for turning on or off power supply.

<sup>\*3</sup> Do not apply a DC bias to the substrate clock and reset gate clock pins, because a DC bias is generated within the CCD.

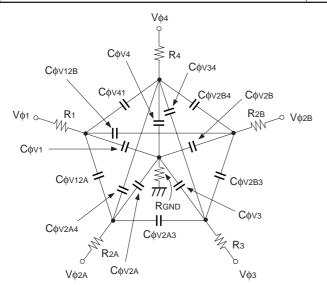
# **Clock Voltage Conditions**

Item	Symbol	Min.	Тур.	Max.	Unit	Waveform Diagram	Remarks
Readout clock voltage	Vvт	14.55	15.0	15.45	V	1	
	Vvh1, Vvh2	-0.05	0	0.05	V	2	VvH = (VvH1 + VvH) /2
	VvH3, VvH4	-0.2	0	0.05	V	2	
	VVL1, VVL2, VVL3, VVL4	-7.3	-7.0	-6.7	٧	2	Vvl = (Vvl3 + Vvl) /2
	Vφv	6.5	7.0	7.35	V	2	$V\phi V = VVHN - VVLN (n = 1 to 4)$
Vertical transfer clock voltage	Vvнз — Vvн	-0.25		0.1	V	2	
voltage	VvH4 — VvH	-0.25		0.1	V	2	
	V∨нн			1.4	V	2	High-level coupling
	Vvhl			1.3	V	2	High-level coupling
	VVLH			1.4	V	2	Low-level coupling
	VVLL			0.8	V	2	Low-level coupling
	Vфн	4.75	5.0	5.25	V	3	
Horizontal transfer clock voltage	VHL	-0.05	0	0.05	V	3	
olook voltago	Vcr	Vфн/2			V	3	Cross-point voltage
	V¢RG	3.0	3.3	5.5	V	4	
Reset gate clock voltage	Vrglh – Vrgll			0.4	V	4	Low-level coupling
101.490	VRGL - VRGLm			0.5	V	4	Low-level coupling
Substrate clock voltage	Vфsuв	21.25	22.0	22.75	V	5	_

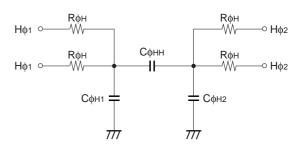
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# **Clock Equivalent Circuit Constants**

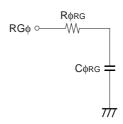
ltem	Symbol	Min.	Тур.	Max.	Unit	Remarks
	Сф∨1		5600		pF	
	СфV2А		6800		pF	
Capacitance between vertical transfer clock and GND	Сф∨2В		22000		pF	
CND	Сф∨з		8200		pF	
	Сф∨4		22000		pF	
	СфV12А		150		pF	
	СфV12В		390		pF	
	Сф∨2А3		270		pF	
Conscitance between vertical transfer clocks	Сф∨2В3		470		pF	
Capacitance between vertical transfer clocks	СфV14		2200		pF	
	Сф∨34		330		pF	
	Сф∨2А4		390		pF	
	Сф∨2В4		560		pF	
Capacitance between horizontal transfer clock	Сфн1		47		pF	
and GND	Сфн2		39		pF	
Capacitance between horizontal transfer clocks	Сфнн		74		pF	
Capacitance between reset gate clock and GND	Сфяс		4		pF	
Capacitance between substrate clock and GND	Сфѕив		1300		pF	
	R1, R3		30		Ω	
Vertical transfer clock series resistor	R2A, R2B		32		Ω	
	R <sub>4</sub>		20		Ω	
Vertical transfer clock ground resistor	RGND		60		Ω	
Horizontal transfer clock series resistor	Rфн		7.5		Ω	
Reset gate clock ground resistor	Rørg		24		Ω	



Vertical transfer clock equivalent circuit



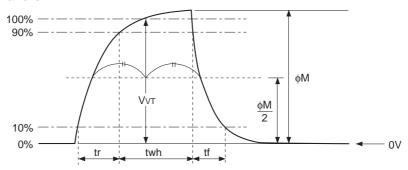
Horizontal transfer clock equivalent circuit



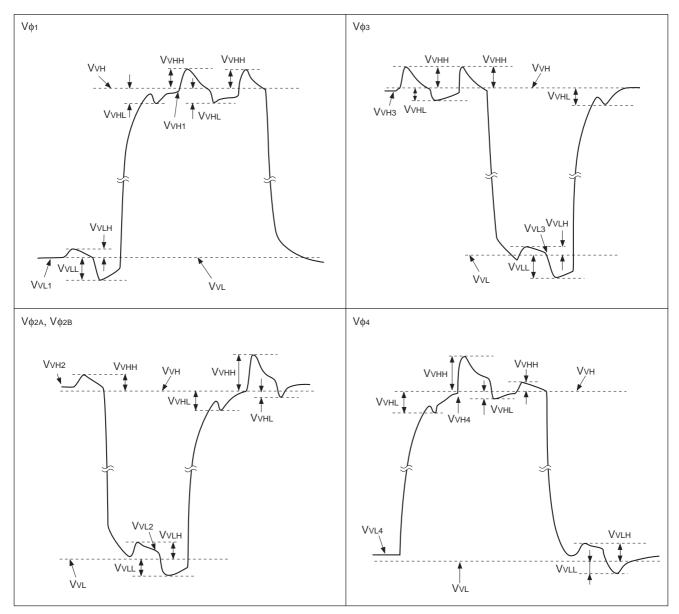
Reset gate clock equivalent circuit

# **Drive Clock Waveform Conditions**

# (1) Readout clock waveform



# (2) Vertical transfer clock waveform

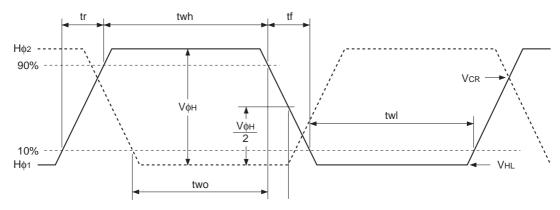


VvH = (VvH1 + VvH2)/2

VvL = (VvL3 + VvL4)/2

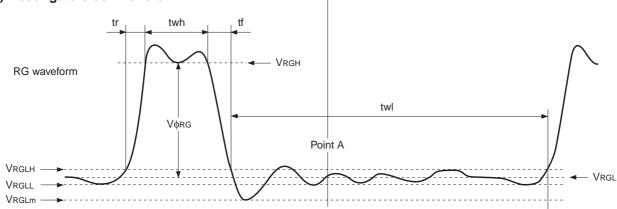
 $V\phi V = VVHN - VVLN (n = 1 to 4)$ 

# (3) Horizontal transfer clock waveform



Cross-point voltage for the  $H\phi_1$  rising side of the horizontal transfer clocks  $H\phi_1$  and  $H\phi_2$  waveforms is Vcr. The overlap period for twh and twl of horizontal transfer clocks  $H\phi_1$  and  $H\phi_2$  is two.

# (4) Reset gate clock waveform



VRGLH is the maximum value and VRGLL is the minimum value of the coupling waveform during the period from Point A in the above diagram until the rising edge of RG.

In addition, VRGL is the average value of VRGLH and VRGLL.

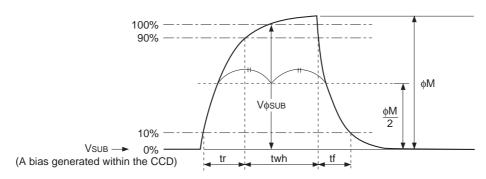
$$V_{RGL} = (V_{RGLH} + V_{RGLL})/2$$

Assuming VRGH is the minimum value during the interval with twh, then:

$$V\phi RG = VRGH - VRGL$$

Negative overshoot level during the falling edge of RG is VRGLm.

# (5) Substrate clock waveform

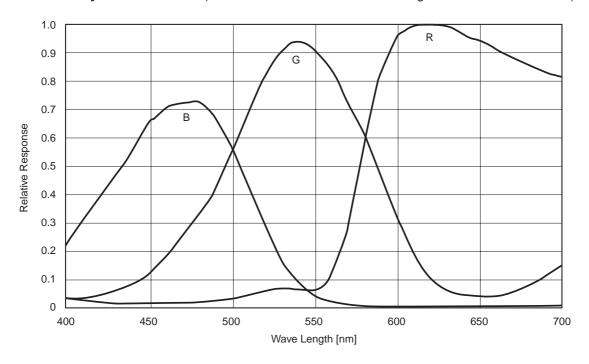


# Clock Switching Characteristics (Horizontal drive frequency: 28.64MHz)

	Item			twh			twl			tr			tf		Unit	Remarks	
	item	Symbol	Min.	Тур.	Мах.	Min.	Тур.	Мах.	Min.	Тур.	Max.	Min.	Тур.	Max.	Offic	Remarks	
Rea	dout clock	VT	2.8	3.0						0.5			0.5		μs	During readout	
Vert cloc	ical transfer k	V\$1, V\$2, V\$3, V\$4										15		250	ns	When using CXD3400N	
tal	During	Нф1	10	12.5		10	12.5			5	7.5		5	7.5	ns t	tf ≥ tr – 2ns	
rtal c	imaging	Нф2	10	12.5		10	12.5			5	7.5		5	7.5		11 2 11 - 2115	
Horizontal transfer clo	During	Нф1								0.01			0.01				
를	parallel-serial conversion	Нф2								0.01			0.01		μs		
Res	et gate clock	φRG	4	8			24			2			2		ns		
Sub	strate clock	φSUB	3.5	3.9							0.5			0.5	μs	During drain charge	

Item	Symbol		two		Unit	Remarks
item	Symbol	Min.	Тур.	Мах.	Offic	Kemarks
Horizontal transfer clock	Нф1, Нф2	8	10		ns	

# Spectral Sensitivity Characteristics (excludes lens characteristics and light source characteristics)



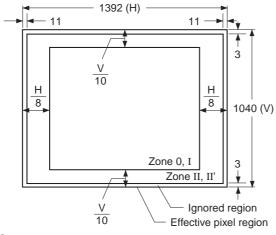
# **Image Sensor Characteristics**

 $(Ta = 25^{\circ}C)$ 

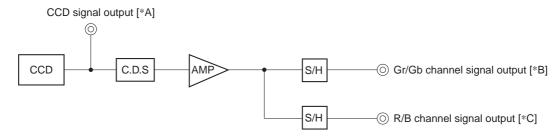
Item		Symbol	Min.	Тур.	Max.	Unit	Measurement method	Remarks
G Sensitivity		Sg		1240		mV	1	1/30s accumulation
Sensitivity	R	Rr	0.40	0.60	0.70		1	
comparison	В	Rb	0.30	0.53	0.60		I	
Saturation sign	nal	Vsat	850			mV	2	Ta = 60°C
Smear		Sm		-110	-100	dB	_	Progressive scan mode
Silleai		SIII		-98	-88	ub	3	High frame rate readout mode
Video signal o	hadina	SHg			20	- %	4	Zone 0 and I
Video signal s	nauing	Sing			25	/0	4	Zone 0 to II'
Dark signal		Vdt			10	mV	5	Ta = 60°C, 15 frames/s
Dark signal sh	ading	ΔVdt			4	mV	6	Ta = 60°C, 15 frames/s, *1
Line crawl G		Lcr			3.8	%	7	
Line crawl R		Lcg			3.8	%	7	
Line crawl B		Lcb			3.8	%	7	
Lag		Lag			0.5	%	8	

<sup>\*1</sup> Excludes vertical dark signal shading caused by vertical register high-speed transfer.

# **Zone Definition of Video Signal Shading**

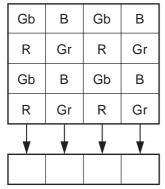


# **Measurement System**



# **Image Sensor Characteristics Measurement Method**

# O Color coding of this image sensor & Readout



The primary color filters of this image sensor are arranged in the layout shown in the figure on the left (Bayer arrangement). Gr and Gb denote the G signals on the same line as the R signal and the B signal, respectively.

Horizontal register

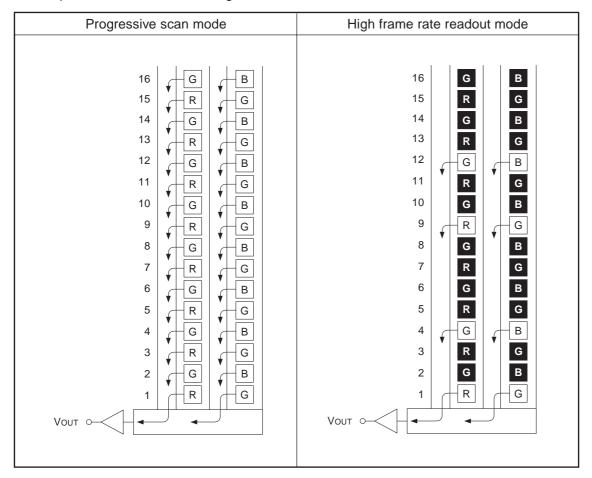
**Color Coding Diagram** 

All pixels' signals are output successively in a 1/15s period.

The R signal and Gr signal lines and the Gb signal and B signal lines are output successively.

#### Readout modes

The output methods for the following two readout modes are shown below.



**Note)** Blacked out portions in the diagram indicate pixels which are not read out. Output starts from line 1 in high frame readout modes.

# 1. Progressive scan mode

In this mode, all pixels' signals are output in non-interlace format in 1/15s.

All pixels' signals within the same exposure period are read out simultaneously, making this mode suitable for high resolution image capturing.

#### 2. High frame rate readout mode

All effective areas are scanned in approximately 1/60s by reading out two out of eight lines (1st and 4th lines, 9th and 12th lines, and so on). The vertical resolution is approximately 256 TV-lines. This readout mode emphasizes processing speed over vertical resolution.

# **Image Sensor Characteristics Measurement Method**

#### Measurement conditions

(1) In the following measurements, the device drive conditions are at the typical values of the bias and clock voltage conditions, and the progressive scan mode is used.

(2) In the following measurements, spot blemishes are excluded and, unless otherwise specified, the optical black level (OB) is used as the reference for the signal output, which is taken as the value of the Gr/Gb signal output or the R/B signal output of the measurement system.

# O Definition of standard imaging conditions

# (1) Standard imaging condition I:

Use a pattern box (luminance: 706cd/m², color temperature of 3200K halogen source) as a subject. (Pattern for evaluation is not applicable.) Use a testing standard lens with CM500S (t = 1.0mm) as an IR cut filter and image at F5.6. The luminous intensity to the sensor receiving surface at this point is defined as the standard sensitivity testing luminous intensity.

#### (2) Standard imaging condition II:

Image a light source (color temperature of 3200K) with a uniformity of brightness within 2% at all angles. Use a testing standard lens with CM500S (t = 1.0mm) as an IR cut filter. The luminous intensity is adjusted to the value indicated in each testing item by the lens diaphragm.

#### 1. Sensitivity, sensitivity comparison

Set to the standard imaging condition I. After setting the electronic shutter mode with a shutter speed of 1/100s, measure the signal outputs (VgR, Vgb, VR and VB) at the center of each Gr, Gb, R and B channel screen, and substitute the values into the following formulas.

$$VG = (VGr + VGb) / 2$$

$$Sg = VG \times \frac{100}{30} [mV]$$

$$Rr = VR/VG$$

$$Rb = VB/VG$$

# 2. Saturation signal

Set to the standard imaging condition II. After adjusting the luminous intensity to 20 times the intensity with the average value of the Gr signal output, 200mV, measure the minimum values of the Gr, Gb, R and B signal outputs.

#### 3. Smear

Set to the standard imaging condition II. With the lens diaphragm at F5.6 to F8, first adjust the average value of the Gr signal output to 200mV. Measure the average values of the Gr signal output, Gb signal output, R signal output and B signal output (Gra, Gba, Ra, Ba), and then adjust the luminous intensity to 500 times the intensity with the average value of the Gr signal output, 200mV.

After the readout clock is stopped and the charge drain is executed by the electronic shutter at the respective H blankings, measure the maximum value (Vsm [mV]) independent of the Gr, Gb, R and B signal outputs, and substitute the values into the following formula.

$$Sm = 20 \times log \ (Vsm \div \frac{Gra + Gba + Ra + Ba}{4} \times \frac{1}{500} \times \frac{1}{10} \ ) \ [dB] \ (1/10V \ method \ conversion \ value)$$

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# 4. Video signal shading

Set to the standard imaging condition III. With the lens diaphragm at F5.6 to F8, adjusting the luminous intensity so that the average value of the Gr signal output is 200mV. Then measure the maximum value (Grmax [mV]) and minimum value (Grmin [mV]) of the Gr signal output and substitute the values into the following formula.

SHg = (Grmax – Grmin) 
$$/200 \times 100$$
 [%]

# 5. Dark signal

Measure the average value of the signal output (Vdt [mV]) with the device ambient temperature of 60°C and the device in the light-obstructed state, using the horizontal idle transfer level as a reference.

#### 6. Dark signal shading

After measuring 5, measure the maximum (Vdmax [mV]) and minimum (Vdmin [mV]) values of the dark signal output and substitute the values into the following formula.

$$\Delta Vdt = Vdmax - Vdmin [mV]$$

#### 7. Line crawl

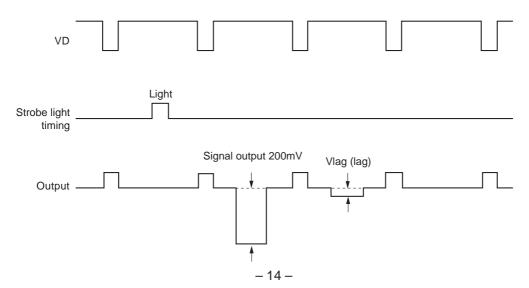
Set to the standard imaging condition II. Adjusting the luminous intensity so that the average value of the Gr signal output is 200mV, and then insert R, G and B filters and measure the difference between G signal lines ( $\Delta$ Glr,  $\Delta$ Glg,  $\Delta$ Glb [mV]) as well as the average value of the G signal output (Gar, Gag, Gab). Substitute the values into the following formula.

$$Lci = \frac{\Delta Gli}{Gai} \times 100 \text{ [\%] (i = r, g, b)}$$

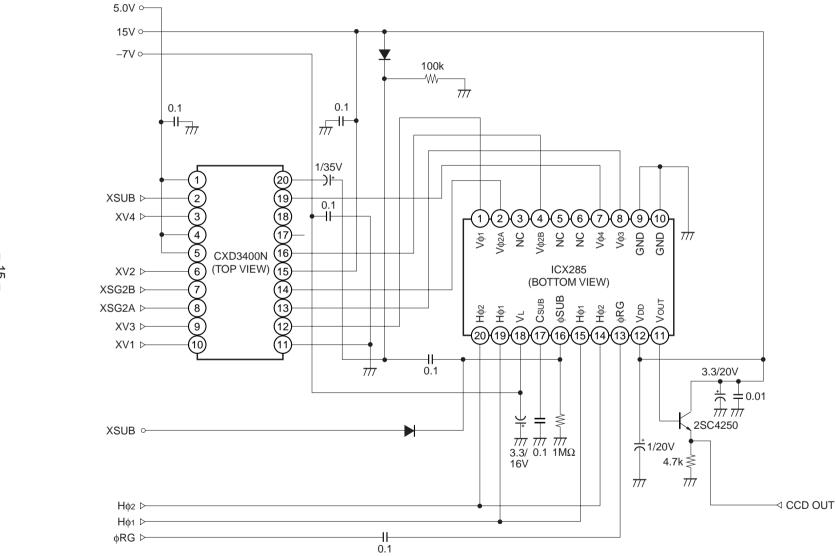
#### 8. Lag

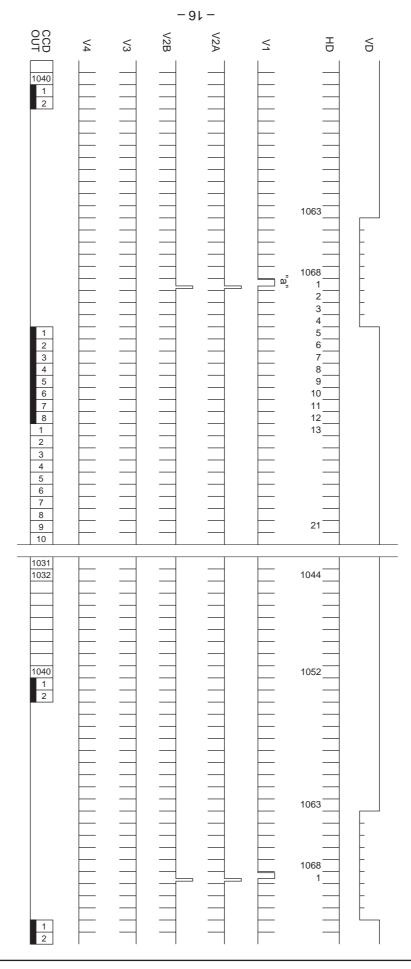
Adjust the Gr signal output value generated by the strobe light to 200mV. After setting the strobe light so that it strobes with the following timing, measure the residual signal amount (Vlag). Substitute the value into the following formula.

$$Lag = (Vlag/20) \times 100 [\%]$$

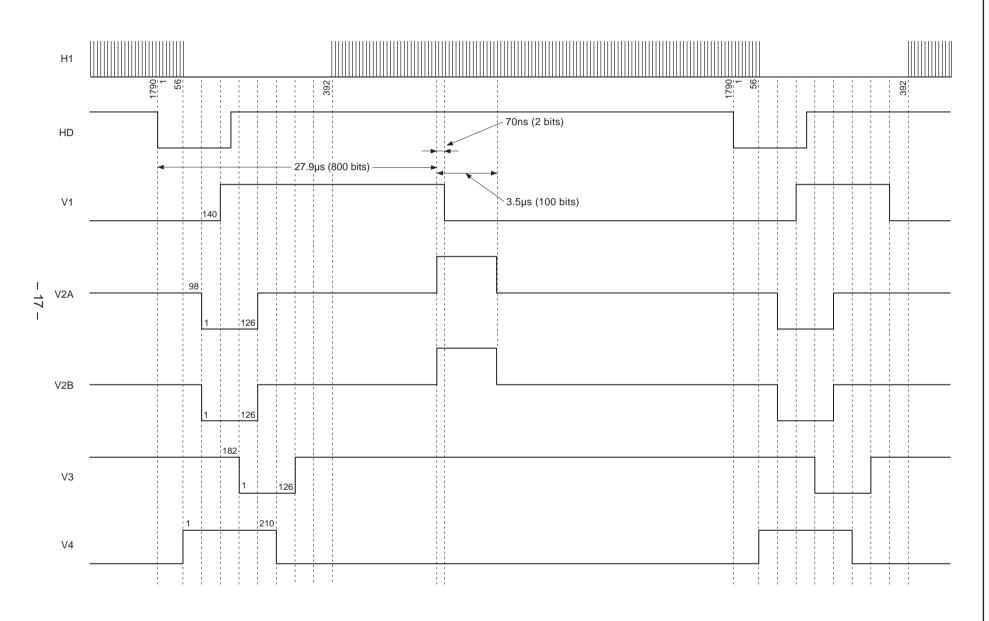


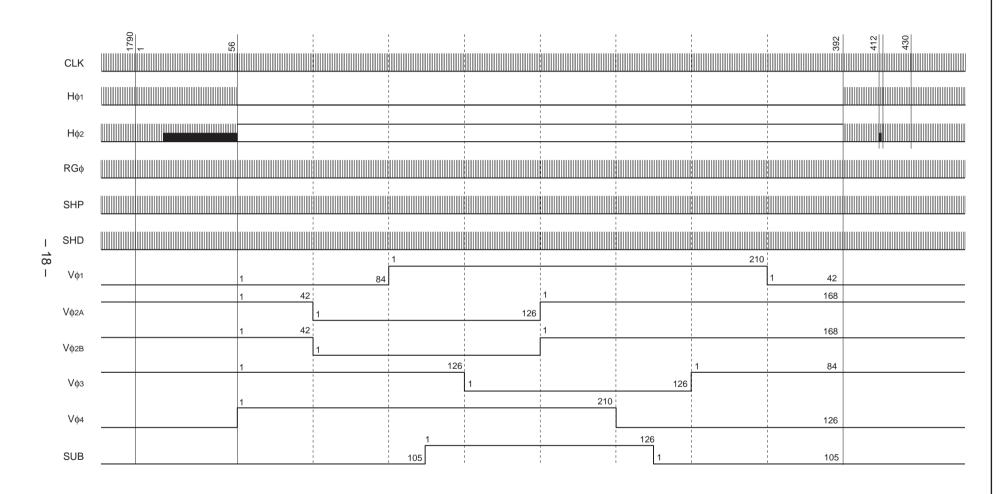
**Drive Circuit** 

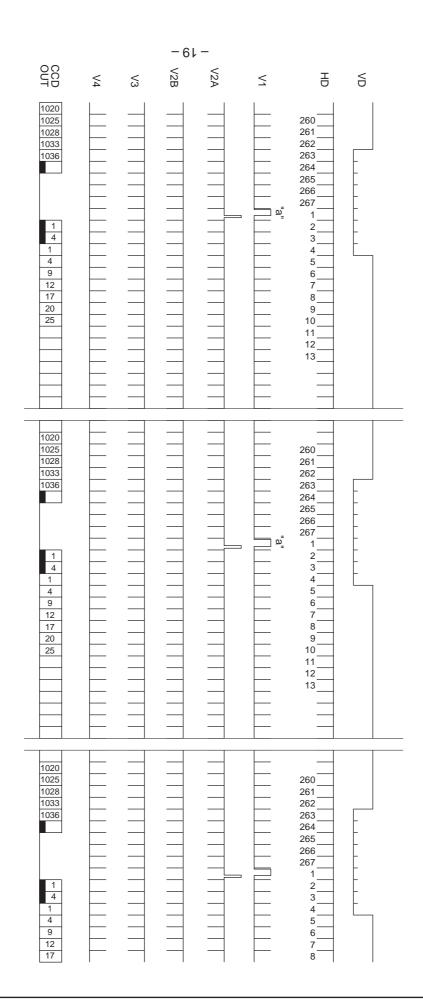




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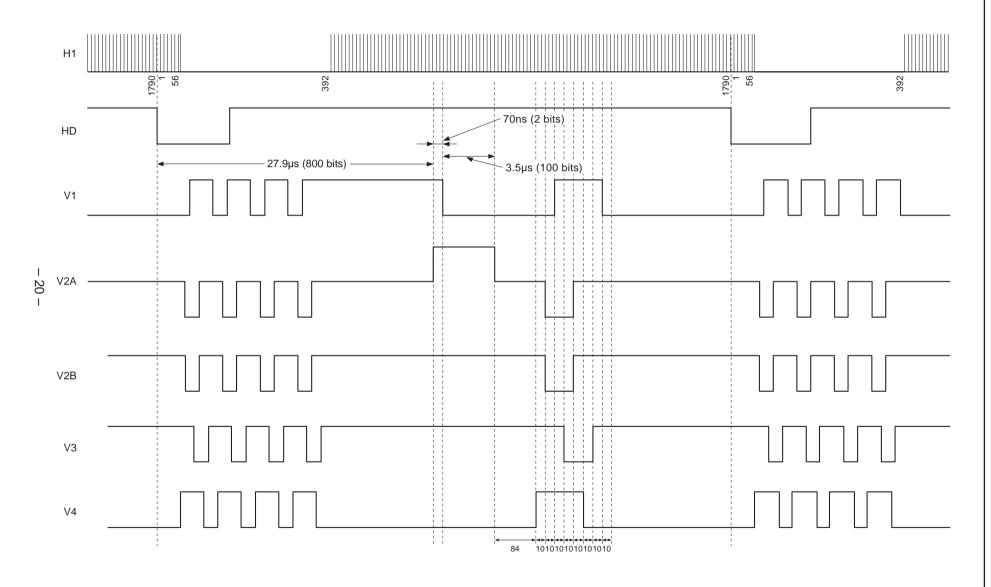


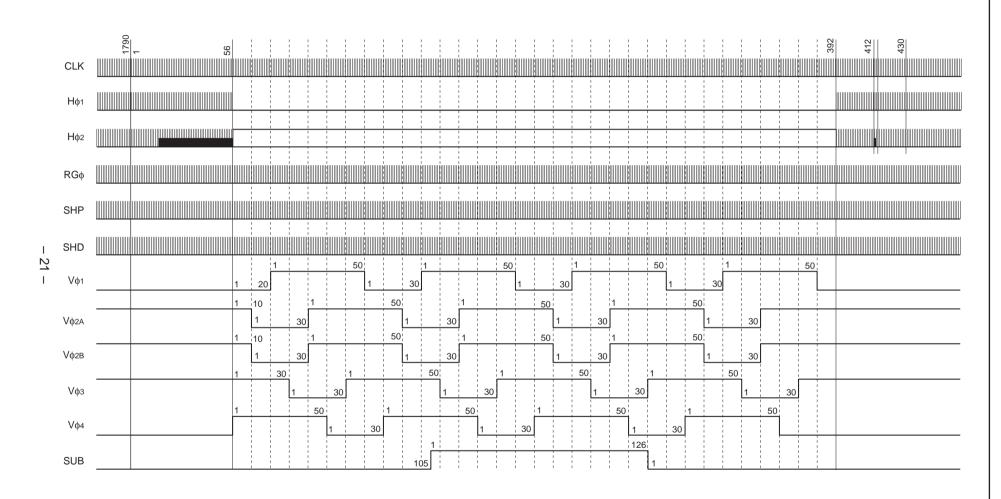




**SONX** 

# Drive Timing Chart (Vertical Sync "a" Enlarged) High Frame Rate Readout Mode





#### **Notes on Handling**

#### 1) Static charge prevention

CCD image sensors are easily damaged by static discharge. Before handling be sure to take the following protective measures.

- a) Either handle bare handed or use non-chargeable gloves, clothes or material. Also use conductive shoes.
- b) When handling directly use an earth band.
- c) Install a conductive mat on the floor or working table to prevent the generation of static electricity.
- d) Ionized air is recommended for discharge when handling CCD image sensors.
- e) For the shipment of mounted substrates, use boxes treated for the prevention of static charges.

#### 2) Soldering

- a) Make sure the package temperature does not exceed 80°C.
- b) Solder dipping in a mounting furnace causes damage to the glass and other defects. Use a ground 30W soldering iron and solder each pin in less than 2 seconds. For repairs and remount, cool sufficiently.
- c) To dismount an image sensor, do not use a solder suction equipment. When using an electric desoldering toll, use a thermal controller of the zero-cross On/Off type and connect it to ground.

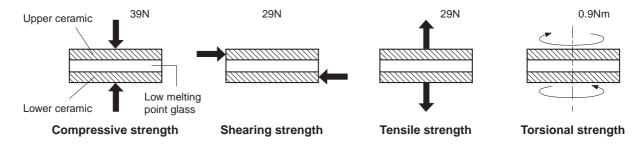
#### 3) Dust and dirt protection

Image sensors are packed and delivered by taking care of protecting its glass plates from harmful dust and dirt. Clean glass plates with the following operations as required, and use them.

- a) Perform all assembly operations in a clean room (class 1000 or less).
- b) Do not either touch glass plates by hand or have any object come in contact with glass surfaces. Should dirt stick to a glass surface, blow it off with an air blower. (For dirt stuck through static electricity ionized air is recommended.)
- c) Clean with a cotton bud and ethyl alcohol if grease stained. Be careful not to scratch the glass.
- d) Keep in a case to protect from dust and dirt. To prevent dew condensation, preheat or precool when moving to a room with great temperature differences.
- e) When a protective tape is applied before shipping, just before use remove the tape applied for electrostatic protection. Do not reuse the tape.

# 4) Installing (attaching)

a) Remain within the following limits when applying a static load to the package. Do not apply any load more than 0.7mm inside the outer perimeter of the glass portion, and do not apply and load or impact to limited portions. (This may cause cracks in the package.)

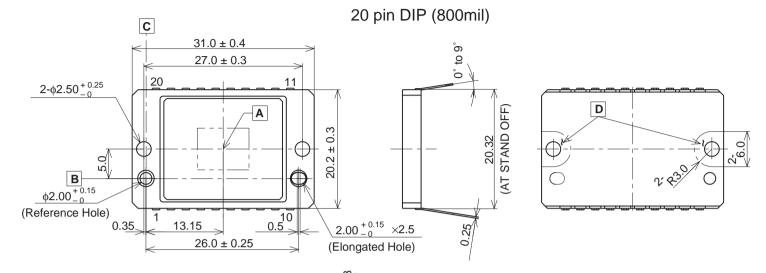


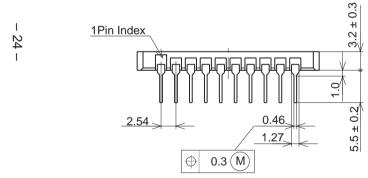
b) If a load is applied to the entire surface by a hard component, bending stress may be generated and the package may fracture, etc., depending on the flatness of the bottom of the package. Therefore, for installation, use an elastic load, such as a spring plate, or an adhesive.

- c) The adhesive may cause the marking on the rear surface to disappear, especially in case the regulated voltage value is indicated on the rear surface. Therefore, the adhesive should not be applied to this area, and indicated values should be transferred to other locations as a precaution.
- d) The upper and lower ceramic are joined by low melting point glass. Therefore, care should be taken not to perform the following actions as this may cause cracks.
  - Applying repeated bending stress to the outer leads.
  - Heating the outer leads for an extended period with a soldering iron.
  - Rapidly cooling or heating the package.
  - Applying any load or impact to a limited portion of the low melting point glass using tweezers or other sharp tools.
  - Prying at the upper or lower ceramic using the low melting point glass as a fulcrum. Note that the same cautions also apply when removing soldered products from boards.
- e) Acrylate anaerobic adhesives are generally used to attach CCD image sensors. In addition, cyanoacrylate instantaneous adhesives are sometimes used jointly with acrylate anaerobic adhesives. (reference)

#### 5) Others

- a) Do not expose to strong light (sun rays) for long periods, as color filters will be discolored. When high luminous objects are imaged with the exposure level controlled by the electronic iris, the luminance of the image-plane may become excessive and discoloring of the color filter will possibly be accelerated. In such a case, it is advisable that taking-lens with the automatic-iris and closing of the shutter during the power-off mode should be properly arranged. For continuous using under cruel condition exceeding the normal using condition, consult our company.
- b) Exposure to high temperature or humidity will affect the characteristics. Accordingly avoid storage or usage in such conditions.
- c) This CCD image sensor has a device structure that is sensitive to near infrared light, so white spots during the subsequent dark signal occur at a higher probability compared to CCD image sensors with normal structures. Therefore, note that the white spot at dark signal specification cannot be guaranteed when used after storage for long periods.





# PACKAGE STRUCTURE

	PACKAGE MATERIAL	Ceramic
	LEAD TREATMENT	GOLD PLATING
	LEAD MATERIAL	42 ALLOY
)	PACKAGE MASS	5.90g
	DRAWING NUMBER	AS-A11(E)

- 1. "A" is the center of the effective image area.
- 2. The straight line "B" which passes through the center of the reference hole and the elongated hole is the reference axis of vertical direction (V).
- 3. The straight line "C" which passes through the center of the reference hole at right angle to vertical reference line "B" is the reference axis of horizontal direction (H).
- 4. The bottom "D" is the height reference.(Two points are specified.)
- 5. The center of the effective image area specified relative to the reference hole is  $(H, V) = (13.15, 5.0) \pm 0.15$ mm.
- 6. The angle of rotation relative to the reference line "B" is less than  $\pm$  1°
- 7. The height from the bottom "D" to the effective image area is 1.46  $\pm$  0.15mm.
- 8. The tilt of the effective image area relative to the bottom " ${f D}$ " is less than 60 $\mu$ m.
- 9. The thickness of the cover glass is 0.75mm and the refractive index is 1.5.